## MSKSEMI















**ESD** 

TVS

TSS

MOV

GDT

**PLED** 

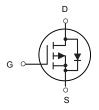
# Broduct data sheet











P-Channel MOSFET

## Description

The SI2333CDS-T1-MS uses advanced trench technology to provide excellent R<sub>DS(ON)</sub>, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

## **General Features**

 $V_{DS} = -18V, I_{D} = -7A$ 

 $R_{DS(ON)}$  < 22m $\Omega$  @  $V_{GS}$ =4.5V

## **Application**

High power and current handing capability
Lead free product is acquired
Surface mount package
PWM applications
Load switch
Power management

## Absolute Maximum Ratings (T<sub>A</sub>=25 ℃ unless otherwise noted)

Symbol	Parameter	Limit	Unit	
V <sub>D</sub> s	Drain-Source Voltage	-18	V	
V <sub>G</sub> s	Gate-Source Voltage	±12	V	
I <sub>D</sub>	Drain Current-Continuous	-7	А	
Ірм	Drain Current-Pulsed (Note 1)	-18.8	А	
P <sub>D</sub>	Maximum Power Dissipation	1	W	
TJ,Tstg	Operating Junction and Storage Temperature Range	-55 To 150	$^{\circ}$ C	
Reja	Thermal Resistance,Junction-to-Ambient (Note 2)	125	°C/W	

## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-18			V	
△BV <sub>DSS</sub> /△T <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.01		V/°C	
		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6.5A		18	22	mΩ	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-5A		25	39		
		V <sub>GS</sub> =-1.8V , I <sub>D</sub> =-1.5A					
V <sub>GS(th)</sub>	Gate Threshold Voltage	\/ -\/   - 250\	-0.6	-0.8	-1.4	V	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$				mV/°C	
	Drain Source Leakage Current	V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1		
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C				uA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =± 12V , V <sub>DS</sub> =0V			±100	nA	
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-3A		10		S	
$Q_g$	Total Gate Charge (-4.5V)			10			
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =-10V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6 <b>A</b> 5		1.5		nC	
$Q_{gd}$	Gate-Drain Charge			3			
T <sub>d(on)</sub>	Turn-On Delay Time			30			
T <sub>r</sub>	Rise Time	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =6.0 $\Omega$		25			
$T_{d(off)}$	Turn-Off Delay Time	I <sub>D</sub> =-1A		70		ns	
T <sub>f</sub>	Fall Time			50			
C <sub>iss</sub>	Input Capacitance			1210			
Coss	Output Capacitance	V <sub>DS</sub> =-10V , V <sub>GS</sub> =0V , f=1MHz		310		pF	
C <sub>rss</sub>	Reverse Transfer Capacitance			290			

### **Diode Characteristics**

Symbol	Parameter	Conditions		Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,4</sup>	-\/ -0\/ Faras Current			-7.0	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-18.8	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup> V <sub>GS</sub>	s=0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1	V
t <sub>rr</sub>	Reverse Recovery Time			52		nS
$Q_{rr}$	Reverse Recovery Charge	4A , dI/dt=100A/µs , T <sub>J</sub> =25°C		28		nC

#### Note

- 1. The data tested by surface mounted on a 1 inch $^2$  FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- 3. The power dissipation is limited by 150°C junction temperature
- 4. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

## **Typical Characteristics**

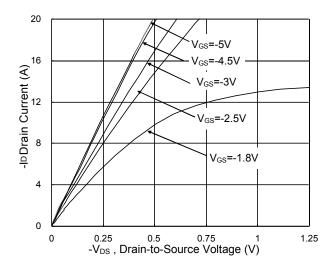


Fig.1 Typical Output Characteristics

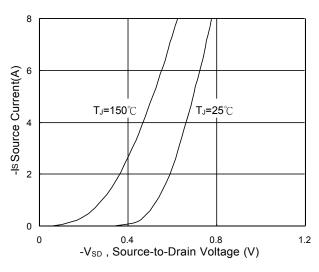


Fig.3 Forward Characteristics Of Reverse

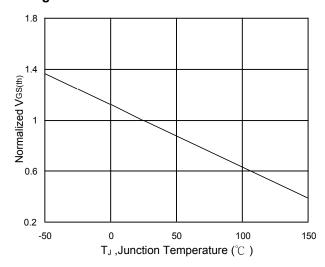


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

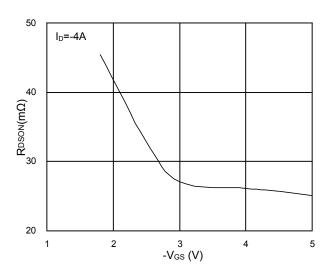


Fig.2 On-Resistance vs. Gate-Source

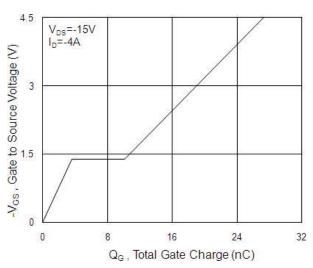


Fig.4 Gate-Charge Characteristics

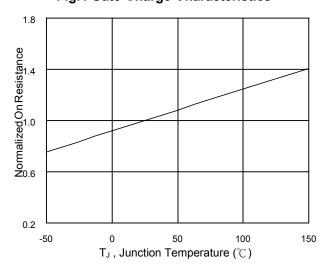
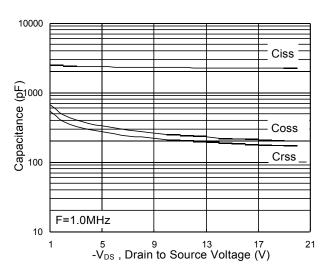


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>



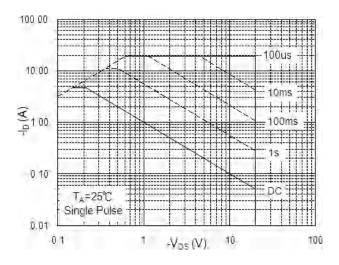


Fig.7 Capacitance

Fig.8 Safe Operating Area

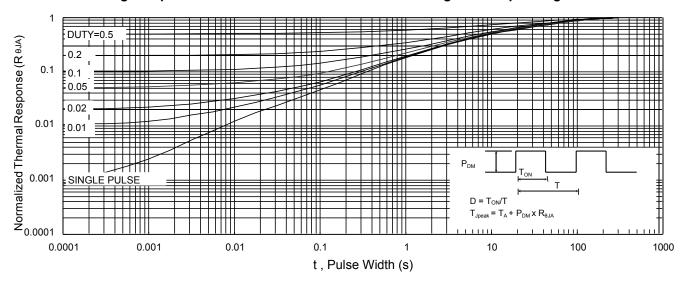
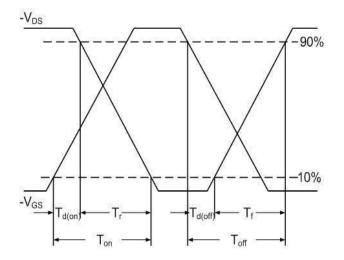
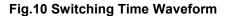


Fig.9 Normalized Maximum Transient Thermal Impedance





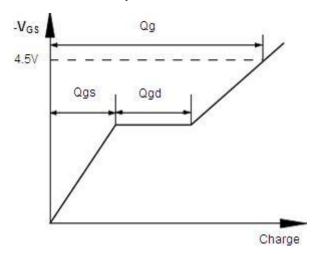
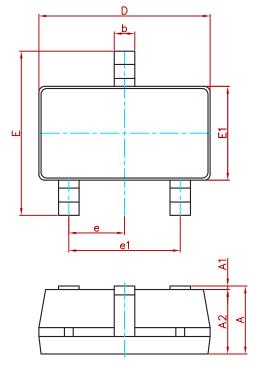


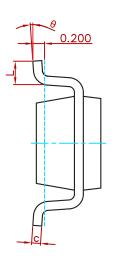
Fig.11 Gate Charge Waveform

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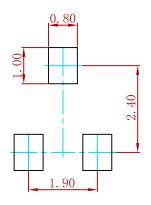
## **PACKAGE MECHANICAL DATA**





Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	1.050	1.250	0.041	0.049	
A1	0.000	0.100	0.000	0.004	
A2	1.050	1.150	0.041	0.045	
b	0.300	0.500	0.012	0.020	
С	0.100	0.200	0.004	0.008	
D	2.820	3.020	0.111	0.119	
E1	1.500	1.700	0.059	0.067	
E	2.650	2.950	0.104	0.116	
е	0.950(	BSC)	0.037(	(BSC)	
e1	1.800	2.000	0.071	0.079	
L	0.300	0.600	0.012	0.024	
θ	0°	8°	0°	8°	

## **Suggested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
SI2333CDS-T1-MS	SOT-23-3L	3000



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DMN1006UCA6-7 DMN16M9UCA6-7 STF5N65M6 IRF40H233XTMA1 IPSA70R950CEAKMA1 IPSA70R2K0CEAKMA1 STU5N65M6
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